ABSTRACT

A scan diagnosis system for testing and diagnosing a device-under-test is disclosed. The system includes a semiconductor tester adapted for coupling to the device-under-test and operative to generate pattern signals in the ATE domain to test the device-under-test and produce test output data in the ATE domain. An ATPG diagnosis tool is operative to generate ATPG pattern data and ATPG results data in the ATPG domain. A translator serves to effect automatic correlation of data between the ATPG domain and the ATE domain to allow data communication between the tester and the tool.

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